

Applicatio	n/Con	trol No.
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10/723,664

Examiner Edan Orgad Applicant(s)/Patent under Reexamination

BURKE ET AL.

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SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
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SEARCH NOT (INCLUDING SEARCH	ΓES STRATEGY	)
	DATE	EXMR
EAST class/subclass search		
NPL: IEEE Xplore	3/26/2007	. EO
Inventor name search		
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